



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.09/559,903
Filing DateApril 26, 2000
Inventor Zhiping Yin et al.
Assignee Micron Technology, Inc.
Group Art Unit..... 2815
Examiner Eckert II, G.
Attorney's Docket No.MI22-1427
Title: Circuitry and Gate Stacks

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: Jennifer J. Taylor, Ph.D. (Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
601 W. First Avenue, Suite 1300
Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449 and copies of which are attached.

Citation of these references is respectfully requested.

A check in the amount of \$180.00 is enclosed to cover the fee specified under 37 C.F.R. § 1.17(p).

Respectfully submitted,

Dated:

August 31, 2004

By:

Jennifer J. Taylor
Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

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| Form PTO-1449 <div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> U.S. DEPT. OF COMMERCE PATENT & TRADEMARK OFFICE AUG 31 2004 </div> | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. M122-1427 | | SERIAL NO. 09/559,903 | |
| LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT Zhiping Yin et al. | | FILING DATE April 26, 2000 | |
| | | | | GROUP 2815 | | | |

| U.S. PATENT DOCUMENTS | | | | | | | |
|-----------------------|-----------------|---------|--------------------|-------|----------|----------------------------|--|
| *Examiner Initial | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| AA | 6,638,875 | 10-2003 | Han et al. | | | | |
| AB | 6,720,247 | 04-2004 | Kirkpatrick et al. | | | | |
| AC | 6,723,631 | 04-2004 | Noguchi et al. | | | | |
| AD | 6,627,535 | 09-2003 | MacNeil et al. | | | | |
| AE | 5,593,741 | 01-1997 | Ikeda | | | | |
| AF | 2003/0077916 | 04-2003 | Xu et al. | | | | |
| AG | 2003/0207594 | 11-2003 | Catabay et al. | | | | |
| AH | 2004/0071878 | 04-2004 | Schuhmacher et al. | | | | |
| AI | | | | | | | |
| AJ | | | | | | | |
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| AL | | | | | | | |

| FOREIGN PATENT DOCUMENTS | | | | | | | |
|--------------------------|------|---------|-------|----------|-------------|----|--|
| Document Number | Date | Country | Class | Subclass | Translation | | |
| | | | | | Yes | No | |
| AM | | | | | | | |
| AN | | | | | | | |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | |
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| EXAMINER | DATE CONSIDERED |
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.